



TESTFORUM 2026

Swissôtel, Tallinn, Estonia
December 1st – 2nd, 2026

Call for Presentations

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Martin Østergaard
GPV, Denmark

William Baars (associate member)
CN Rood, The Netherlands

Test Forum 2026 Local Organizer

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The 2-day TestForum 2026, the 24th event in the series, is the major event for Test professionals in the Nordic area and the Baltic states. Every year the TestForum is attended by key people from the industrial test community as well as by international vendors of test and measurement equipment and solutions.

This year the event will take place in downtown Tallinn, at a very close proximity to the UNESCO Heritage medieval core of the city – the Old Town.

Nordic Test Forum hereby cordially invites you to participate and submit your contribution to TestForum 2026, which includes (but is not limited to) the following topics:

- *Functional Test*
- *Boundary Scan Test*
- *Embedded Instruments*
- *RF Test*
- *AOI / AXI / SPI*
- *ICT / Flying Probe*
- *Fixturing / Interfaces*
- *Power Test / Battery Test*
- *Test efficiency/optimization*
- *Test automation, Robotics*
- *Design for Testability*
- *AI in test, Prognostics*
- *Hardware-in-the-loop test*
- *SLT (System Level Test)*
- *Board test software, BIST, POST, diagnostics*
- *Best practices in manufacturing test*
- *Security, safety & other regulations for test*
- *Test economics*
- *Quality methods and tools*
- *Future technology trends and new test challenges*
- *Big data acquisition / collection / analysis*
- *Test of electronics in automotive, defense and industrial applications*
- *Product validation*
- *Design to Test transfer*
- *R&D in measurements, fault and test cases*

Submissions

TestForum seeks presentations in the area of test of electronics, including *R&D, Application Contributions, Best Practices, Emerging Ideas*, etc. You are welcome to submit contributions also outside the above topics as long as they stay within the field of electronics test. Focus shall be on new and emerging challenges, opportunities, techniques and best practices in electronics test technology rather than on particular products. *Marketing presentations are only allowed during the exhibitor session!* **Submission format:** Send a title and a short abstract of the proposed presentation for selection process (see the secretary email below).

Proceedings

The accepted contributions of authors that wish to provide the corresponding materials will be delivered in electronic format at the Nordic Test Forum event.

The Format of the Event

- The event format is a two-day conference/workshop and a small exhibition attached to it.
- November 30th in the evening there is the Annual General Meeting of the NTF.
- The number/duration of sessions is defined by the mix of presentations (approx. 20).
- The presentations are 30 minutes each: 25 minutes of speech and 5 minutes for Q&A.
- Companies are invited to arrange table-top demos at the exhibition area, where a table will be provided to exhibitors.
- In the exhibition, attendees will have an opportunity to see the latest equipment and solutions, talk to exhibitors and experts.

Key Dates

- Abstract submission:
- Notification of acceptance:
- Conference registration opens:
- Presentation slides:

31st August
11th September
16th September
6th November

Information and Submissions

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Visit the NTF web pages at
<http://www.nordictestforum.org>

